

Notice of References Cited	Application/Control No. 10/526,309	Applicant(s)/Patent Under Reexamination HARTHERZ, PATRIK	
	Examiner Jason M. Greene	Art Unit 1797	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,557,340 B1	05-2003	Twigg et al.	60/311
*	B	US-6,976,353 B2	12-2005	Daniel et al.	60/311
*	C	US-2002/0170433 A1	11-2002	Pfeifer et al.	95/285
*	D	US-2005/0241295 A1	11-2005	Breuer et al.	060/311
*	E	US-6,176,078 B1	01-2001	Balko et al.	60/274
*	F	US-7,135,153 B2	11-2006	Bartley et al.	422/168
*	G	US-6,185,930 B1	02-2001	Lepperhoff et al.	60/274
*	H	US-6,546,720 B2	04-2003	van Nieuwstadt, Michiel Jacques	60/286
*	I	US-2004/0037755 A1	02-2004	Mital et al.	60/297
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	DE 34 40 689 A1	05-1986	Germany	Siemens AG	B01D 53/34
	O	EP 1 544 425 A1	06-2005	EPO	NGK Insulators Ltd.	F01N 3/02
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.